









**THVD2412, THVD2442** SLLSFR1A - NOVEMBER 2023 - REVISED MARCH 2024

# THVD24x2 ±70V Fault-Protected 3V to 5.5V Full Duplex RS-485 Transceivers With IEC **ESD**

#### 1 Features

- Meets or exceeds the requirements of the TIA/ EIA-485A and TIA/EIA-422B standards
- 3V to 5.5V supply voltage
- Differential output exceeds 2.1V for PROFIBUS compatibility with 5V supply
- Bus I/O protection
  - ±70V DC bus fault
  - ±16kV HBM ESD
  - ±8kV IEC 61000-4-2 contact discharge
  - ±8kV IEC 61000-4-2 air-gap discharge
  - ±4kV IEC 61000-4-4 fast transient burst
- Full-duplex devices available in two speed grades
  - THVD2412: 250kbps
  - THVD2442: 20Mbps
- Extended ambient temperature range: -40°C to
- Extended operational common-mode range: ±25V
- Enhanced receiver hysteresis for noise immunity
- Low power consumption
  - Low shutdown supply current: < 10μA</li>
  - Current during operation: < 5.6mA</li>
- Glitch-free power-up/down for hot plug-in capability
- Open, short, and idle bus failsafe
- Thermal shutdown
- 1/8 unit load (up to 256 bus nodes) in 7V to 12V common mode range
- Small 3mm x 3mm VSON package to save board space

# 2 Applications

- Motor drives
- Factory automation and control
- **HVAC** systems
- **Building automation**
- Grid infrastructure
- Electricity meters
- Process analytics
- Video surveillance

### 3 Description

THVD2412 and THVD2442 are ±70V fault-protected, full-duplex, RS-422/RS-485 transceivers operating on a single 3V to 5.5V supply. Bus interface pins are protected against overvoltage conditions during all modes of operation ensuring robust communication in rugged industrial environments.

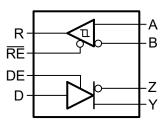
devices feature integrated **IEC** eliminating the need for system-level protection components. Extended ±25V input common-mode range ensures reliable data communication over longer cable run lengths and/or in the presence of large ground loop voltages. Enhanced 250mV receiver hysteresis provides high noise rejection. In addition, the receiver fail-safe feature provides a logic high when the bus inputs are open or shorted together.

THVD24x2 devices are available in small and thermally efficient VSON packages for spaceconstrained applications. These devices characterized over ambient temperature from -40°C to 125°C.

#### Package Information

PART NUMBER	PACKAGE <sup>(1)</sup>	PACKAGE SIZE(2)
THVD2412 THVD2442	VSON (10)	3mm × 3mm

- For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.



THVD2412 and THVD2442 Simplified Schematic



# **Table of Contents**

1 Features	1	7.2 Functional Block Diagrams	14
2 Applications		7.3 Feature Description	
3 Description		7.4 Device Functional Modes	
4 Pin Configuration and Functions		8 Application and Implementation	17
5 Specifications	4	8.1 Application Information	17
5.1 Absolute Maximum Ratings		8.2 Typical Application	
5.2 ESD Ratings	4	8.3 Power Supply Recommendations	22
5.3 ESD Ratings [IEC]	4	8.4 Layout	
5.4 Recommended Operating Conditions	5	9 Device and Documentation Support	24
5.5 Thermal Information	5	9.1 Device Support	24
5.6 Power Dissipation	5	9.2 Receiving Notification of Documentation Update	s <mark>2</mark> 4
5.7 Electrical Characteristics	6	9.3 Support Resources	24
5.8 Switching Characteristics_250kbps	8	9.4 Trademarks	24
5.9 Switching Characteristics_20Mbps		9.5 Electrostatic Discharge Caution	24
5.10 Typical Characteristics		9.6 Glossary	
6 Parameter Measurement Information		10 Revision History	
7 Detailed Description	14	11 Mechanical, Packaging, and Orderable	
7.1 Overview		Information	24



# **4 Pin Configuration and Functions**

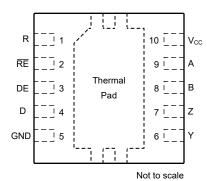


Figure 4-1. DRC (VSON), 10-Pin Package, Top View

Table 4-1. Pin Functions

PIN		TYPE	DESCRIPTION
NAME	DRC	ITPE	DESCRIPTION
R	1	Digital output	Receive data output
RE	2	Digital input	Receiver enable input; integrated weak pull-up (~2 MΩ)
DE	3	Digital input	Driver enable input; integrated weak pull-down (~2 MΩ)
D	4	Digital input	Transmission data input; integrated weak pull-up (~2 MΩ)
GND	5	Ground	Local Device ground
Υ	6	Bus output	Driver non-inverting output
Z	7	Bus output	Driver inverting output
В	8	Bus input	Receiver inverting bus input
A	9	Bus input	Receiver non-inverting bus input
V <sub>CC</sub>	10	Power	3 V to 5.5 V supply voltage
Thermal Pad	_	_	No electrical connection. Should be connected to GND plane for optimal thermal performance



# **5 Specifications**

# 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1) (2)

		MIN	MAX	UNIT
Supply voltage	Vcc	-0.5	6.5	V
Bus voltage	Range at any bus pin as differential or common-mode with respect to GND	-70	70	V
Input voltage	Range at any logic pin (D, DE, or RE)	-0.3	5.7	V
Receiver output current	lo	-24	24	mA
Storage temperature	T <sub>stg</sub>	-65	170	°C

- (1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) All voltage values, except differential I/O bus voltages, are with respect to ground terminal.

### 5.2 ESD Ratings

				VALUE	UNIT
	Human-body model (HBM), per ANSI/ESDA/	Bus terminals and GND	±16,000	V	
V <sub>(ESD)</sub>	Electrostatic discharge	JEDEC JS-001 <sup>(1)</sup>	All pins except bus terminals and GND	±4,000	V
		Charged-device model (CDM), per JEDEC specifi	±1,500	V	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

# 5.3 ESD Ratings [IEC]

				VALUE	UNIT
V <sub>(ESD)</sub> (1) Electrostatic discharge	Contact discharge, per IEC 61000-4-2	Bus terminals and GND	±8,000	V	
	Electrostatic discharge	Air-gap discharge, per IEC 61000-4-2	Bus terminals and GND	±8,000	V
V <sub>(EFT)</sub>	Electrical fast transient	Per IEC 61000-4-4	Bus terminals	±4,000	V

(1) For optimised IEC ESD performance, it is recommended to have series resistor (≥ 50 Ω) on all logic inputs to minimize transient currents going into or out of the logic pins.



# **5.4 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)

		,	MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		3		5.5	V
VI	Input voltage at any bus term	inal (separately or common mode) <sup>(1)</sup>	-25		25	V
V <sub>IH</sub>	High-level input voltage (drive	er, driver enable, and receiver enable inputs)	2		5.5	V
V <sub>IL</sub>	Low-level input voltage (drive	r, driver enable, and receiver enable inputs)	0		0.8	V
V <sub>ID</sub>	Differential input voltage bus	-25		25	V	
Io	Output current, driver		-60		60	mA
I <sub>OR</sub>	Output current, receiver		-8		8	mA
R <sub>L</sub>	Differential load resistance		54	60		Ω
1/t <sub>UI</sub>	Signaling rate	THVD2412			250	kbps
ויינון	Signaling rate	THVD2442			20	Mbps
T <sub>A</sub>	Operating ambient temperatu	Operating ambient temperature			125	°C
TJ	Junction temperature		-40		150	°C

<sup>(1)</sup> The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

### 5.5 Thermal Information

		THVD2412 THVD2442	
	THERMAL METRIC(1)	DRC (VSON)	UNIT
		10 PINS	
R <sub>0JA</sub>	Junction-to-ambient thermal resistance	46.7	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	47.7	°C/W
R <sub>eJB</sub>	Junction-to-board thermal resistance	19.1	°C/W
ΨЈТ	Junction-to-top characterization parameter	0.7	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	19.1	°C/W
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	4.6	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

# 5.6 Power Dissipation

PARAMETER		TEST CONDITIONS			VALUE	UNIT
P <sub>D</sub>		Unterminated	THVD2412	250 kbps	258	mW
	Driver and receiver enabled, loopback	$R_L = 300 \Omega$ , $C_L = 50 pF (driver)$	THVD2442	20 Mbps	335	IIIVV
	(connect A to Y, B to Z)	RS-422 load R <sub>L</sub> = 100 $\Omega$ , C <sub>L</sub> = 50 pF (driver)	THVD2412	250 kbps	273	mW
	V <sub>CC</sub> = 5.5 V, T <sub>A</sub> = 125 °C, random data (PRBS7) at signaling rate		THVD2442	20 Mbps	325	IIIVV
	Tandom data (FRBS1) at signaling rate	RS-485 load R <sub>L</sub> = 54 Ω, C <sub>L</sub> = 50 pF (driver)	THVD2412	250 kbps	315	mW
			THVD2442	20 Mbps	355	IIIVV



# **5.7 Electrical Characteristics**

over operating free-air temperature range (unless otherwise noted). All typical values are at  $25^{\circ}$ C and supply voltage of  $V_{CC} = 5 \text{ V}$ .

	PARAMETER	TI	EST CONDITIONS		MIN	TYP	MAX	UNIT
Driver								
		$R_L$ = 60 Ω, -25 V ≤ $V_{test}$ ≤ 25 V	V, See Figure 6-1		1.5	2.8		V
	Driver differential output	R <sub>L</sub> = 60 Ω, -25 V ≤ V <sub>test</sub> ≤ 25 V		See Figure 6-1	2.1	3.3		V
Driver   Driver	voltage magnitude	R <sub>L</sub> = 100 Ω, See Figure 6-2			2	2.9		V
		$R_L$ = 54 Ω, See Figure 6-2			1.5	2.5		V
$\Delta  V_{OD} $	Change in differential output voltage	$R_L$ = 54 $\Omega$ or 100 $\Omega$ , See Figure	re 6-2		-50		50	mV
V <sub>oc</sub>	Common-mode output voltage	$R_L$ = 54 $\Omega$ or 100 $\Omega$ , See Figure	re 6-2		1	V <sub>CC</sub> /2	3	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage	$R_L$ = 54 $\Omega$ or 100 $\Omega$ , See Figure	re 6-2		-50		50	mV
I <sub>OS</sub>	Short-circuit output current	DE = V <sub>CC</sub> , -70 V ≤ (V <sub>Y</sub> or V <sub>Z</sub> ):	≤ 70 V, or Y shorted to	Z	-250		250	mA
Receiver								
				V <sub>I</sub> = 12 V		75	125	μA
	Bus input current	DE = 0 V, V <sub>CC</sub> = 0 V or 5.5 V	DE = 0 V, V <sub>CC</sub> = 0 V	V <sub>I</sub> = 25 V		200	250	μA
l <sub>l</sub>			or 5.5 V	V <sub>I</sub> = -7 V	-100	-60		μA
				V <sub>I</sub> = -25 V	-350	-350		μA
V <sub>TH+</sub>	Positive-going input threshold voltage <sup>(1)</sup>	Over common-mode range of	± 25 V		20	125	200	mV
V <sub>TH-</sub>	Negative-going input threshold voltage <sup>(1)</sup>	Over common-mode range of	± 25 V		-200	-125	-20	mV
V <sub>HYS</sub>	Input hysteresis	Over common-mode range of	± 25 V			250		mV
V <sub>TH_FSH</sub>	Input fail-safe threshold	Over common-mode range of	± 25 V		-20		20	mV
C <sub>A,B</sub>	Input differential capacitance	Measured between A and B, f	= 1 MHz			50		pF
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -8 mA			V <sub>CC</sub> - 0.4	V <sub>CC</sub> – 0.2		V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> = 8 mA				0.2	0.4	V
I <sub>OZ</sub>	Output high-impedance current	$V_{O} = 0 \text{ V or } V_{CC}, \overline{RE} = V_{CC}$			-1		1	μA
Logic								
I <sub>IN</sub>	Input current (DE)	3 V ≤ V <sub>CC</sub> ≤ 5.5 V, 0 V ≤ V <sub>IN</sub> ≤	V <sub>CC</sub>				5	μA
I <sub>IN</sub>	Input current (D, RE)	$3 \text{ V} \le \text{V}_{CC} \le 5.5 \text{ V}, 0 \text{ V} \le \text{V}_{IN} \le$	V <sub>CC</sub>		-5			μA
Thermal P	Protection						'	
T <sub>SHDN</sub>	Thermal shutdown threshold	Temperature rising			150	170		°C
T <sub>HYS</sub>	Thermal shutdown hysteresis					10		°C
Supply		•			-			
UV <sub>VCC</sub>	Rising under-voltage threshold on V <sub>CC</sub>					2.3	2.6	V
UV <sub>VCC</sub>	Falling under-voltage threshold on V <sub>CC</sub>				1.95	2.2		V
UV <sub>VCC(hys</sub>	Hysteresis on under-voltage of V <sub>CC</sub>					150		mV



# **5.7 Electrical Characteristics (continued)**

over operating free-air temperature range (unless otherwise noted). All typical values are at  $25^{\circ}$ C and supply voltage of  $V_{CC}$  = 5 V.

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
I <sub>cc</sub>		Driver and receiver enabled	RE = 0 V, DE = V <sub>CC</sub> , No load		3.5	5.3	mA
	Supply current (quiescent),	Driver enabled, receiver disabled	$\overline{RE}$ = V <sub>CC</sub> , DE = V <sub>CC</sub> , No load		2.5	4.2	mA
I'CC	V <sub>CC</sub> = 4.5 V to 5.5 V	Driver disabled, receiver enabled	RE = 0 V, DE = 0 V, No load		1.8	5.3 4.2 2.4 7 4.1	mA
		Driver and receiver disabled	RE = V <sub>CC</sub> , DE = 0 V, D = open, No load		0.1	7	μA
		Driver and receiver enabled	RE = 0 V, DE = V <sub>CC</sub> , No load		3	4.1	mA
	Supply current (quiescent),	Driver enabled, receiver disabled	$\overline{RE} = V_{CC}$ , DE = $V_{CC}$ , No load		2	5.3 4.2 2.4 7 4.1 3 2.2	mA
ICC	V <sub>CC</sub> = 3 V to 3.6 V	Driver disabled, receiver enabled	RE = 0 V, DE = 0 V, No load		1.6	2.2	mA
		Driver and receiver disabled	RE = V <sub>CC</sub> , DE = 0 V, D = open, No load		0.1	5	μA

<sup>(1)</sup> Under any specific conditions,  $V_{TH+}$  is specified to be at least  $V_{HYS}$  higher than  $V_{TH-}$ .



# 5.8 Switching Characteristics\_250kbps

250-kbps (THVD2412) over recommended operating conditions. All typical values are at 25°C and supply voltage of  $V_{CC}$  = 5 V , unless otherwise noted.

	PARAMETER	TEST CO	NDITIONS	MIN	TYP	MAX	UNIT
Driver			<u>'</u>				
	Differential output rise/fall time		V <sub>CC</sub> = 3 to 3.6 V, Typical at 3.3V	450	650	1200	ns
t <sub>r</sub> , t <sub>f</sub>	Dinerential output rise/fail time		V <sub>CC</sub> = 4.5 to 5.5 V, Typical at 5 V	500	710	1200	ns
	Propagation delay	$R_L = 54 \Omega, C_L = 50 pF$	V <sub>CC</sub> = 3 to 3.6 V, Typical at 3.3V		525	750	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation delay	See Figure 6-3	V <sub>CC</sub> = 4.5 to 5.5 V, Typical at 5 V		560	770	ns
	Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>		V <sub>CC</sub> = 3 to 3.6 V, Typical at 3.3V		30	70	ns
t <sub>SK(P)</sub> F	ruise skew, [tpHL — tpLH]		V <sub>CC</sub> = 4.5 to 5.5 V, Typical at 5 V		30	70	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time	RE = X			33	75	ns
	Enable time	RE = 0 V	See Figure 6-4		400	280	ns
t <sub>PZH</sub> , t <sub>PZL</sub>		RE = V <sub>CC</sub>	and Figure 6-5		2	4.5	μs
t <sub>SHDN</sub>	Time to shutdown	RE = V <sub>CC</sub>		50		500	ns
Receiver						'	
t <sub>r</sub> , t <sub>f</sub>	Output rise/fall time				13	20	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation delay	C <sub>L</sub> = 15 pF	See Figure 6-6		850	1270	ns
t <sub>SK(P)</sub>	Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>				5	45	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time	DE = X	See Figure 6-7		30	40	ns
t <sub>PZH(1)</sub>	Fig. bl. disc.	DE - V	Con Firmer C 7		90	120	ns
t <sub>PZL(1)</sub>	Enable time	DE = V <sub>CC</sub>	See Figure 6-7		900	1320	ns
t <sub>PZH(2)</sub> , t <sub>PZL(2)</sub>	Enable time	DE = 0 V	See Figure 6-8		3.3	5.4	μs
t <sub>D(OFS)</sub>	Delay to enter fail-safe operation	C = 15 pE	See Figure 6-9	7	11	18	μs
t <sub>D(FSO)</sub>	Delay to exit fail-safe operation	- C <sub>L</sub> = 15 pF	See Figure 0-9	540	850	1260	ns
t <sub>SHDN</sub>	Time to shutdown	DE = 0 V	See Figure 6-8	50		500	ns

# **5.9 Switching Characteristics\_20Mbps**

20-Mbps (THVD2442) over recommended operating conditions. All typical values are at  $25^{\circ}$ C and supply voltage of  $V_{CC} = 5$  V, unless otherwise noted

	PARAMETER	TEST C	MIN	TYP	MAX	UNIT		
Driver								
	Differential output via /fall time		V <sub>CC</sub> = 3 to 3.6 V, Typical at 3.3 V	4	8	15	ns	
t <sub>r</sub> , t <sub>f</sub>	Differential output rise/fall time  L, t <sub>PLH</sub> Propagation delay  Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>		V <sub>CC</sub> = 4.5 to 5.5 V, Typical at 5 V	4	7	15	ns	
	t <sub>PLH</sub> Propagation delay	R <sub>1</sub> = 54 Ω, C <sub>1</sub> = 50 pF	$R_L$ = 54 Ω, $C_L$ = 50 pF	V <sub>CC</sub> = 3 to 3.6 V, Typical at 3.3 V	6	15	30	ns
t <sub>PHL</sub> , t <sub>PLH</sub>		See Figure 6-3	V <sub>CC</sub> = 4.5 to 5.5 V, Typical at 5 V	6	13	26	ns	
	Dulas akaw It t		V <sub>CC</sub> = 3 to 3.6 V, Typical at 3.3 V		1	3	ns	
t <sub>SK(P)</sub>	Pulse skew,  LPHL - LPLH		V <sub>CC</sub> = 4.5 to 5.5 V, Typical at 5 V		1	3	ns	
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time	RE = X			15	35	ns	
		RE = 0 V	See Figure 6-4		8	39	ns	
t <sub>PZH</sub> , t <sub>PZL</sub>	Enable time	RE = V <sub>CC</sub>	and Figure 6-5		2	4.5	μs	
t <sub>SHDN</sub>	Time to shutdown	RE = V <sub>CC</sub>		50		500	ns	



# 5.9 Switching Characteristics\_20Mbps (continued)

20-Mbps (THVD2442) over recommended operating conditions. All typical values are at 25°C and supply voltage of  $V_{CC}$  = 5 V, unless otherwise noted

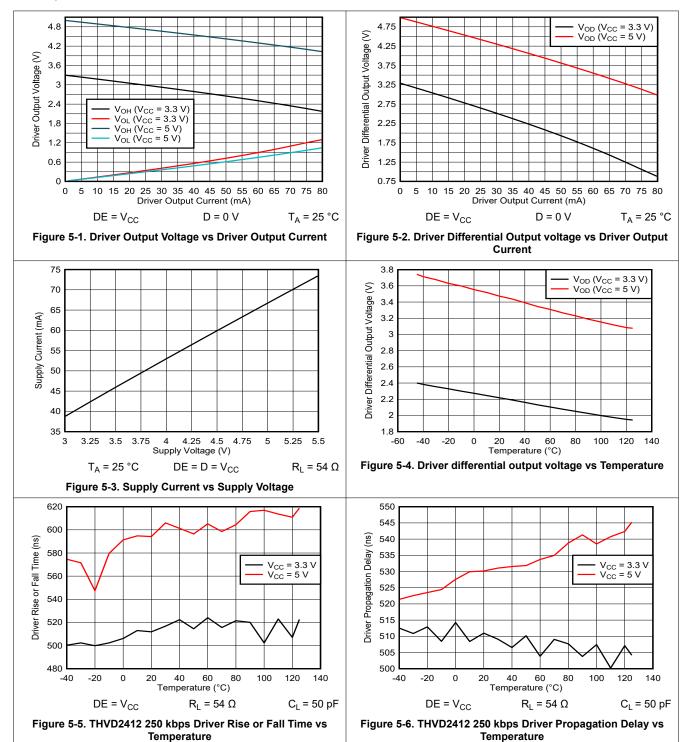
	PARAMETER	TEST COND	MIN	TYP	MAX	UNIT	
Receiver				•			
t <sub>r</sub> , t <sub>f</sub>	Output rise/fall time				1.5	6	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation delay	C <sub>L</sub> = 15 pF	See Figure 6-6		40	57	ns
t <sub>SK(P)</sub>	Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>					5	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time	DE = X	See Figure 6-7		11	25	ns
t <sub>PZH(1)</sub> , t <sub>PZL(1)</sub>	Enable time	DE = V <sub>CC</sub>	See Figure 6-7		55	82	ns
t <sub>PZH(2)</sub> , t <sub>PZL(2)</sub>	Enable time	DE = 0 V	See Figure 6-8		1.5	4.5	μs
t <sub>D(OFS)</sub>	Delay to enter fail-safe operation	C <sub>I</sub> = 15 pF	See Figure 6-9	7	11	18	μs
t <sub>D(FSO)</sub>	Delay to exit fail-safe operation	O <sub>L</sub> = 13 μι	See Figure 0-9	22	25	50	ns
t <sub>SHDN</sub>	Time to shutdown	DE = 0 V	See Figure 6-8	50		500	ns

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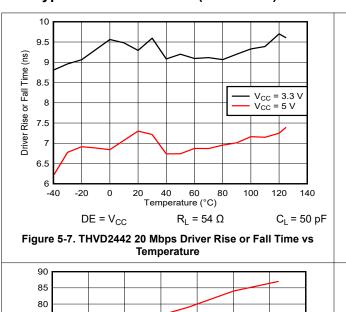


### 5.10 Typical Characteristics





# **5.10 Typical Characteristics (continued)**



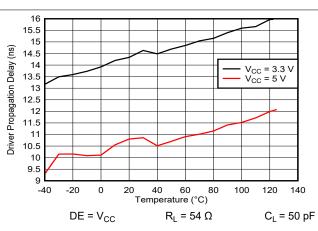


Figure 5-8. THVD2442 20 Mbps Driver Propagation Delay vs Temperature

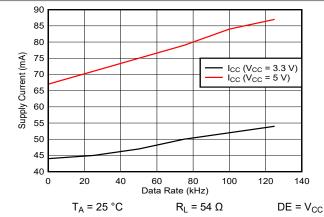


Figure 5-9. THVD2412 Supply Current vs Signal Rate

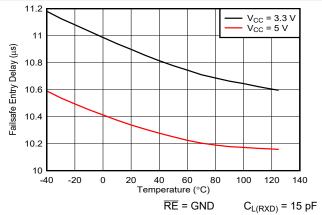


Figure 5-10. Failsafe entry delay vs Temperature

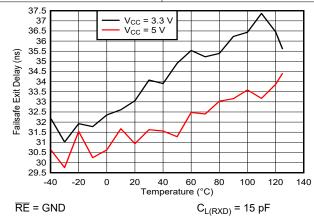


Figure 5-11. Failsafe exit delay vs Temperature



#### **6 Parameter Measurement Information**

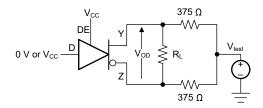


Figure 6-1. Measurement of Driver Differential Output Voltage With Common-Mode Load

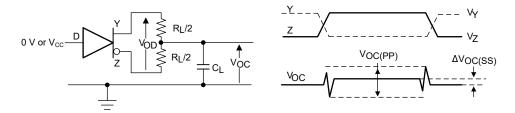


Figure 6-2. Measurement of Driver Differential and Common-Mode Output With RS-485 Load

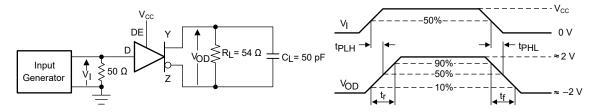


Figure 6-3. Measurement of Driver Differential Output Rise and Fall Times and Propagation Delays

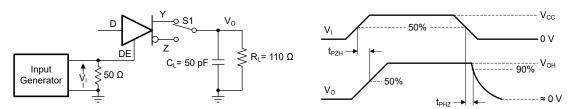


Figure 6-4. Measurement of Driver Enable and Disable Times With Active High Output and Pull-Down Load

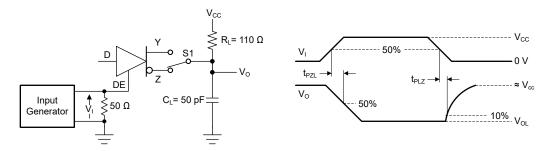


Figure 6-5. Measurement of Driver Enable and Disable Times With Active Low Output and Pull-up Load

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Figure 6-6. Measurement of Receiver Output Rise and Fall Times and Propagation Delays

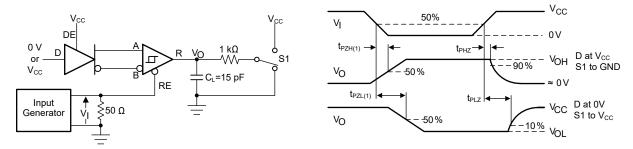


Figure 6-7. Measurement of Receiver Enable/Disable Times With Driver Enabled

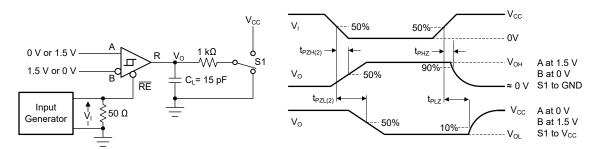
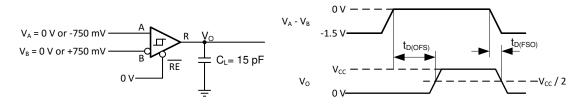


Figure 6-8. Measurement of Receiver Enable Times With Driver Disabled



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Figure 6-9. Measurement of Fail-Safe Delay

## 7 Detailed Description

#### 7.1 Overview

THVD2412 and THVD2442 are fault-protected, full-duplex RS-485/RS-422 transceivers available in 10-VSON package. THVD2412 allows for data transmission up to 250kbps, while THVD2442 is suitable for data transmission up to 20Mbps. The devices have active-high driver enable and active-low receiver enable. A shutdown current of less than 10µA can be achieved by disabling both driver and receiver.

### 7.2 Functional Block Diagrams

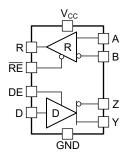


Figure 7-1. THVD24x2 Block Diagram

#### 7.3 Feature Description

#### 7.3.1 ±70-V Fault Protection

THVD24x2 transceivers have extended bus fault protection compared to standard RS-485 devices. Transceivers that operate in rugged industrial environments are often exposed to voltage transients greater than the -7 V to +12 V defined by the TIA/EIA-485A standard. To protect against such conditions, the generic RS-485 devices with lower absolute maximum ratings requires expensive external protection components. To simplify system design and reduce overall system cost, THVD24x2 devices are protected up to ±70 V without the need for any external components.

#### 7.3.2 Integrated IEC ESD and EFT Protection

Internal ESD protection circuits protect the transceivers against electrostatic discharges (ESD) according to IEC 61000-4-2 of up to ±8 kV and against electrical fast transients (EFT) according to IEC 61000-4-4 of up to ±4 kV. Bus structures also protect against electrical fast transients (EFT) according to IEC 61000-4-4 for up to ±4 kV. With careful system design, integrated bus structures can enable EFT Criterion A at the system level (minimum to no data loss when transient noise is present).

#### 7.3.3 Driver Overvoltage and Overcurrent Protection

The THVD24x2 drivers are protected against any DC supply shorts in the range of -70 V to +70 V. The devices internally limit the short circuit current to ±250 mA to comply with the TIA/EIA-485A standard. In addition, a fold-back current limiting circuit reduces the driver short circuit current to less than ±5 mA if the output fault voltage exceeds |±25 V|.

If the junction temperature exceeds the T<sub>SHDN</sub> threshold due to excessive power dissipation, the devices feature thermal shutdown protection that disables the driver and the receiver

### 7.3.4 Enhanced Receiver Noise Immunity

The differential receivers of THVD24x2 feature fully symmetric thresholds to maintain duty cycle of the signal even with small input amplitudes. In addition, 250 mV (typical) receiver hysteresis provides enhanced noise immunity. For THVD2412, typical 700 ns of glitch filter in receiver signal chain prevents high frequency noise pulses from the bus to appear on R pin.



### 7.3.5 Receiver Fail-Safe Operation

The receivers are fail-safe to invalid bus states caused by the following:

- · Open bus conditions, such as a disconnected connector
- Shorted bus conditions, such as cable damage shorting the twisted-pair together
- · Idle bus conditions that occur when no driver on the bus is actively driving

In any of these cases, the receiver outputs a fail-safe logic high state if the input amplitude stays for longer than  $t_{D(OFS)}$  at less than  $|V_{TH\ FSH}|$ .

#### 7.3.6 Low-Power Shutdown Mode

Driving DE low and  $\overline{RE}$  high for longer than 500 ns puts the devices into the shutdown mode. If either DE goes high or  $\overline{RE}$  goes low, the counters reset. The devices does not enter the shutdown mode if the enable pins are in disable state for less than 50 ns. This feature prevents the devices from accidentally going into shutdown mode due to skew between DE and  $\overline{RE}$ .

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#### 7.4 Device Functional Modes

When the driver enable pin, DE, is logic high, the differential outputs Y and Z follow the logic states at data input D. A logic high at D causes Y to turn high and Z to turn low. In this case, the differential output voltage defined as  $V_{OD} = V_Y - V_Z$  is positive. When D is low, the output states reverse: Z turns high, Y becomes low, and  $V_{OD}$  is negative.

When DE is low, both outputs turn high-impedance. In this condition, the logic state at D is irrelevant. The DE pin has an internal pull-down resistor to ground, thus when left open the driver is disabled (high-impedance) by default. The D pin has an internal pull-up resistor to  $V_{CC}$ , thus, when left open while the driver is enabled, output Y turns high and Z turns low.

Table 7-1. Driver i direttori fable										
FUNCTION	PUTS	OUTI	ENABLE	INPUT						
FUNCTION	Z	Y	DE	D						
Actively drive bus high	L	Н	Н	Н						
Actively drive bus low	Н	L	Н	L						
Driver disabled	Z	Z	L	Х						
Driver disabled by default	Z	Z	OPEN	Х						
Actively drive bus high by default	L	Н	Н	OPEN						

**Table 7-1. Driver Function Table** 

When the receiver enable pin,  $\overline{RE}$ , is logic low, the receiver is enabled. When the differential input voltage defined as  $V_{ID} = V_A - V_B$  is higher than the positive input threshold,  $V_{TH+}$ , the receiver output, R, turns high. When  $V_{ID}$  is lower than the negative input threshold,  $V_{TH-}$ , the receiver output, R, turns low. If  $V_{ID}$  is between  $V_{TH+}$  and  $V_{TH-}$ , the output is indeterminate.

When  $\overline{RE}$  is logic high or left open, the receiver output is high-impedance and the magnitude and polarity of  $V_{ID}$  are irrelevant. Internal biasing of the receiver inputs causes the output to go fail-safe high when the transceiver is disconnected from the bus (open-circuit), or the bus lines are shorted to one another (short-circuit), or the bus is not actively driven (idle bus).

DIFFERENTIAL INPUT	ENABLE	OUTPUT	FUNCTION
$V_{ID} = V_A - V_B$	RE	R	FUNCTION
$V_{TH+} < V_{ID}$	L	Н	Receive valid bus high
$V_{TH-} < V_{ID} < V_{TH+}$	L	?	Indeterminate bus state
V <sub>ID</sub> < V <sub>TH-</sub>	L	L	Receive valid bus low
X	Н	Z	Receiver disabled
X	OPEN	Z	Receiver disabled by default
Open-circuit bus	L	Н	Fail-safe high output
Short-circuit bus	L	Н	Fail-safe high output
Idle (terminated) bus	L	Н	Fail-safe high output

Table 7-2. Receiver Function Table

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## 8 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 8.1 Application Information

THVD2412 and THVD2442 are fault-protected, full-duplex RS-485 transceivers commonly used for asynchronous data transmissions. For these devices, the driver and receiver enable pins allow for the configuration of different operating modes.

# 8.2 Typical Application

An RS-485 bus consists of multiple transceivers connecting in parallel to a bus cable. To eliminate line reflections, each cable end is terminated with a termination resistor,  $R_T$ , whose value matches the characteristic impedance,  $Z_0$ , of the cable. This method, known as parallel termination, generally allows for higher data rates over longer cable length.

Also note that a full-duplex RS-485 transceiver can be used as a half-duplex transceiver in an application by externally connecting driver output pins Y and Z to receiver input pins A and B respectively.

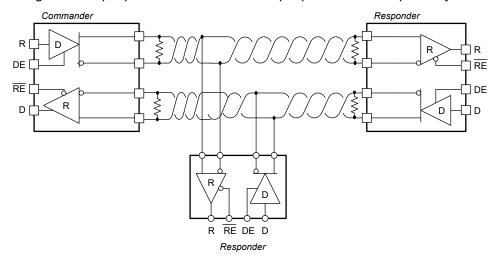


Figure 8-1. Typical RS-485 Network With Full-Duplex Transceivers

### 8.2.1 Design Requirements

RS-485 is a robust electrical standard suitable for long-distance networking that may be used in a wide range of applications with varying requirements, such as distance, data rate, and number of nodes.

#### 8.2.1.1 Data Rate and Bus Length

There is an inverse relationship between data rate and cable length, which means the higher the data rate, the short the cable length; and conversely, the lower the data rate, the longer the cable length. While most RS-485 systems use data rates between 10 kbps and 100 kbps, some applications require data rates up to 250 kbps at distances of 4000 feet and longer. Longer distances are possible by allowing for small signal jitter of up to 5 or 10%.

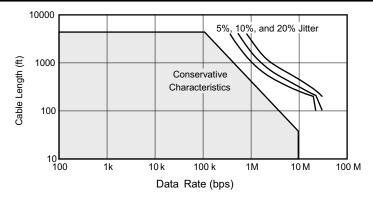


Figure 8-2. Cable Length vs Data Rate Characteristic

Even higher data rates are achievable (that is, 20 Mbps for the THVD2442) in cases where the interconnect is short enough (or has suitably low attenuation at signal frequencies) to not degrade the data.

#### 8.2.1.2 Stub Length

When connecting a node to the bus, the distance between the transceiver inputs and the cable trunk, known as the stub, should be as short as possible. Stubs present a non-terminated piece of bus line which can introduce reflections of varying phase as the length of the stub increases. As a general guideline, the electrical length, or round-trip delay, of a stub should be less than one-tenth of the rise time of the driver, thus giving a maximum physical stub length as shown in Equation 1.

$$L_{(STUB)} \le 0.1 \times t_r \times v \times c \tag{1}$$

#### where

- t<sub>r</sub> is the 10/90 rise time of the driver
- c is the speed of light (3 × 10<sup>8</sup> m/s)
- v is the signal velocity of the cable or trace as a factor of c

#### 8.2.1.3 Bus Loading

The RS-485 standard specifies that a compliant driver must be able to drive 32 unit loads (UL), where 1 unit load represents a load impedance of approximately 12 k $\Omega$ . Because the THVD24x2 devices consist of 1/8 UL transceivers which is approximately 96 k $\Omega$  input impedance, connecting up to 256 receivers to the bus is possible for a limited common mode range of - 7 V to 12 V.

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#### 8.2.1.4 Transient Protection

The bus pins of the THVD24x2 transceivers include on-chip ESD protection against  $\pm 16$ -kV HBM and  $\pm 8$ -kV IEC 61000-4-2 contact discharge. The International Electrotechnical Commission (IEC) ESD test is far more severe than the HBM ESD test. The 50% higher charge capacitance,  $C_{(S)}$ , and 78% lower discharge resistance,  $R_{(D)}$ , of the IEC model produce significantly higher discharge currents than the HBM model. As stated in the IEC 61000-4-2 standard, contact discharge is the preferred transient protection test method.

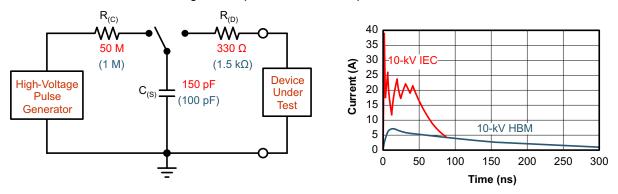


Figure 8-3. HBM and IEC ESD Models and Currents in Comparison (HBM Values in Parenthesis)

The on-chip implementation of IEC ESD protection significantly increases the robustness of equipment. Common discharge events occur because of human contact with connectors and cables. Designers may choose to implement protection against longer duration transients, typically referred to as surge transients.

EFTs are generally caused by relay-contact bounce or the interruption of inductive loads. Surge transients often result from lightning strikes (direct strike or an indirect strike which induce voltages and currents), or the switching of power systems, including load changes and short circuit switching. These transients are often encountered in industrial environments, such as factory automation and power-grid systems.

Figure 8-4 compares the pulse-power of the EFT and surge transients with the power caused by an IEC ESD transient. The left side of Figure 8-4 shows the relative pulse-power for a 0.5-kV surge transient and 4-kV EFT transient, both of which dwarf the 10-kV ESD transient visible in the lower-left corner. 500-V surge transients are representative of events that may occur in factory environments in industrial and process automation.

The right side of Figure 8-4 shows the pulse power of a 6-kV surge transient, relative to the same 0.5-kV surge transient. 6-kV surge transients are most likely to occur in power generation and power-grid systems.

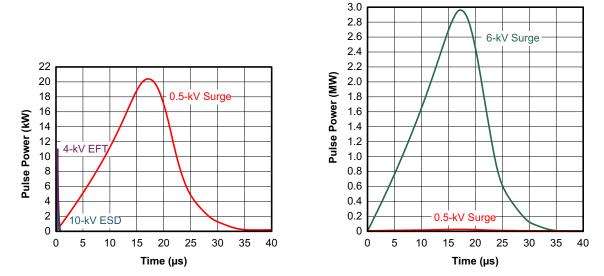


Figure 8-4. Power Comparison of ESD, EFT, and Surge Transients

For surge transients, high-energy content is characterized by long pulse duration and slow decaying pulse power. The electrical energy of a transient that is dumped into the internal protection cells of a transceiver is converted into thermal energy, which heats and destroys the protection cells, thus destroying the transceiver. Figure 8-5 shows the large differences in transient energies for single ESD, EFT, surge transients, and an EFT pulse train that is commonly applied during compliance testing.

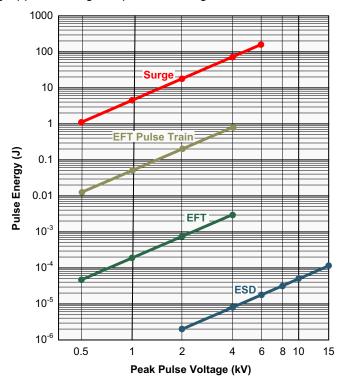


Figure 8-5. Comparison of Transient Energies

# 8.2.2 Detailed Design Procedure

Figure 8-6 suggests a protection circuit against 1 kV surge (IEC 61000-4-5) transients. Table 8-1 shows the associated bill of materials. SMAJ30CA TVS diodes are rated to operate up to 30 V. This makes sure the protection diodes do not conduct if a direct RS-485 bus shorts to 24-V DC industrial power rail.

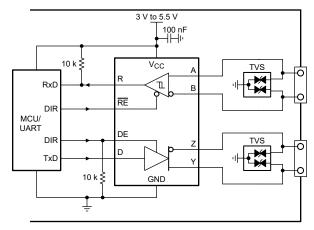


Figure 8-6. Transient Protection Against Surge Transients for Half-Duplex Devices

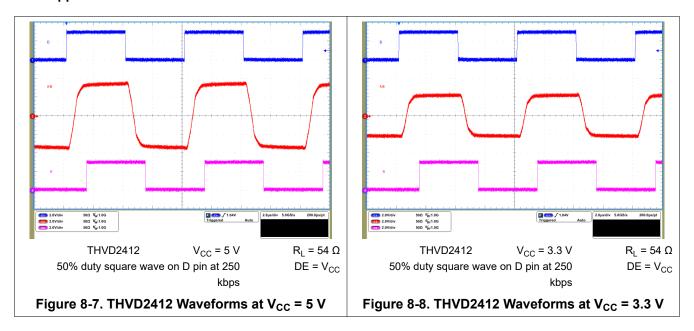
**Table 8-1. Components List** 

DEVICE	FUNCTION	ORDER NUMBER	MANUFACTURER
XCVR	RS-485 transceiver	THVD2412 or THVD2442	TI
TVS	Bidirectional 400-W transient suppressor	SMAJ30CA	Littelfuse <sup>(1)</sup>

(1) See Third-Party Products



### 8.2.3 Application Curves



## 8.3 Power Supply Recommendations

For reliable operation at all data rates and supply voltages,  $V_{CC}$  supply can be decoupled with a 100nF ceramic capacitor located as close to the device supply pin as possible. This reduces supply voltage ripple present on the outputs of switched-mode power supplies, and compensates for the resistance and inductance of the PCB power planes.

#### 8.4 Layout

#### 8.4.1 Layout Guidelines

Robust and reliable bus node design often requires the use of external transient protection devices in order to protect against surge transients that may occur in industrial environments. Since these transients have a wide frequency bandwidth (from approximately 3MHz to 300MHz), high-frequency layout techniques should be applied during PCB design.

- 1. Place the protection circuitry close to the bus connector to prevent noise transients from propagating across the board.
- 2. Use V<sub>CC</sub> and ground planes to provide low inductance. Note that high-frequency currents tend to follow the path of least impedance and not the path of least resistance.
- 3. Design the protection components into the direction of the signal path. Do not force the transient currents to divert from the signal path to reach the protection device.
- 4. Apply 100nF to 220nF decoupling capacitors as close as possible to the V<sub>CC</sub> pins of transceiver, UART and/or controller ICs on the board.
- 5. Use at least two vias for V<sub>CC</sub> and ground connections of decoupling capacitors and protection devices to minimize effective via inductance.
- 6. Use  $1k\Omega$  to  $10k\Omega$  pull-up and pull-down resistors for enable lines to limit noise currents in these lines during transient events.

#### 8.4.2 Layout Example

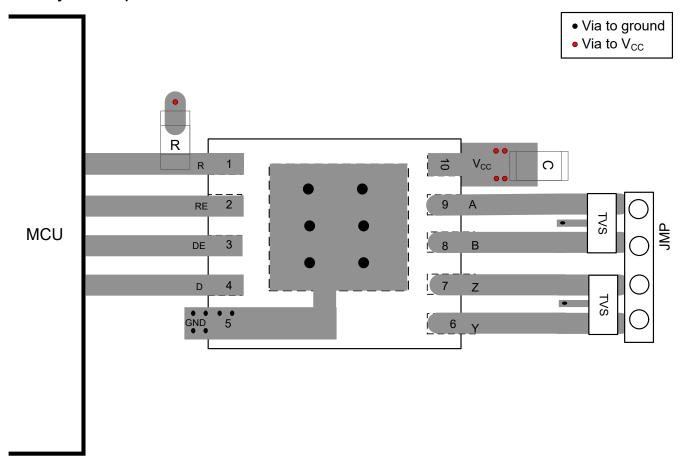


Figure 8-9. Full-Duplex Layout Example

# 9 Device and Documentation Support

## 9.1 Device Support

## 9.1.1 Third-Party Products Disclaimer

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### 9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 9.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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### 9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

#### 10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

#### Changes from Revision \* (November 2023) to Revision A (March 2024)

Page

# 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 8-Nov-2025

#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
THVD2412DRCR	Active	Production	VSON (DRC)   10	5000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2412
THVD2412DRCR.A	Active	Production	VSON (DRC)   10	5000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2412
THVD2442DRCR	Active	Production	VSON (DRC)   10	5000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2442
THVD2442DRCR.A	Active	Production	VSON (DRC)   10	5000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2442

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

# **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THVD2412DRCR	VSON	DRC	10	5000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
THVD2442DRCR	VSON	DRC	10	5000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

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### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THVD2412DRCR	VSON	DRC	10	5000	367.0	367.0	35.0
THVD2442DRCR	VSON	DRC	10	5000	367.0	367.0	35.0

3 x 3, 0.5 mm pitch

PLASTIC SMALL OUTLINE - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC SMALL OUTLINE - NO LEAD



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



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NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



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NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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